## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination SA ET AL. Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0085496	05-2004	Paukshto et al.	349/106
	В	US-2002/0113931	08-2002	Park et al.	349/141
	С	US-6,259,505	07-2001	Makino, Naoki	349/153
	D	US-2002/0163616	11-2002	Jones et al.	349/187
	E	US-2003/0002154	01-2003	Trapani et al.	359/492
	F	US-2002/0196382	12-2002	Ishino, Takayuki	349/43
	G	US-			·
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			-
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	O					
	R					
	S					
	Т				-	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.